

Minutes

Meeting Date: 26 July 2021
Meeting Time: 8 AM – 9:30 AM CDT
Location: Online Meeting

A. Call to order

The meeting of the thermal testing ad hoc (under the oversight of the IEEE C37.13 Working Group) was called to order at 8:05 am CDT.

B. Approval of agenda

Version 1.0 of the proposed meeting agenda was approved by unanimous consent.

C. Attendance

Introductions were made of all attendees. Attendees are listed below.

Eleven ad hoc members were in attendance.

Attendees:

Name	Company	Member/Guest
Keith Flowers	Siemens Industry, Inc.	Chair
Ted Burse	Powell Industries, Inc.	Member
Clint Carne	Schneider Electric	Member
Dan Delfino	ABB	Member
Lou Grahor	Eaton Corporation	Member
Tom Hawkins	Siemens Industry, Inc.	Member
Michael Lafond	ABB	Member
Albert Livshitz	CE Power	Member
Richard Rohr	Powell Industries, Inc.	Member
Eddie Wilkie	Eaton Corporation	Member
Danish Zia	UL LLC	Member

D. Rules and guidelines for conducting working group meetings

The IEEE Patent Policy and Business Conduct slides were reviewed. For reference, they may be found at the following website:

<https://mentor.ieee.org/myproject/Public/mytools/mob/slideset.pdf>

A call for essential patents was made, however none were brought to the attention of the ad hoc.

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E. New business

Thermal testing of low-voltage power circuit breakers and low-voltage switchgear was discussed. Some areas of investigation were identified by the team:

- Maximum ventilation limits for circuit breaker test enclosure faces?
- Circuit breaker test conductors:
 - Standard lists the minimum length of the test conductors. Should there be limitation to length of test conductors? Should there be a temperature delta limitation for the test conductors?
 - Standard is silent on phase-spacings of test conductors. Should there be limits to phase spacings of test conductors?
 - Standard is silent on coatings of test conductors. Should there be limitation or restrictions against coatings of test conductors?
 - The test conductors and circuit breaker terminals are tested in free air. Should the test conductors and/or terminals be enclosed?
- Requirements of the test enclosure (mock compartment) will be reviewed and compared between IEEE Std PC37.13 and IEEE Std C37.20.1.
- Method for determining temperature stabilization should be reviewed between IEEE Std PC37.13 and IEEE Std C37.20.1 for potential harmonization (if there are differences noted).

The team will also review other industry standards for power switching devices for potential best-practices.

F. Next steps discussion

The team will further explore the topics listed in New Business in a follow-up discussion targeted for late August 2021 (specific date and time to-be-determined by poll).

G. Adjourn

The ad hoc completed the agenda and adjourned the meeting at 9:15 am CDT.

Minutes submitted by:
Keith Flowers
Ad Hoc Chair
July 26, 2021